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ECL Products	

100112

Quad Driver

FEATURES

- Typical propagation delay: 0.85ns for data inputs, 1.4ns for Enable Input
- Typical supply current ($-I_{EE}$): 73mA

DESCRIPTION

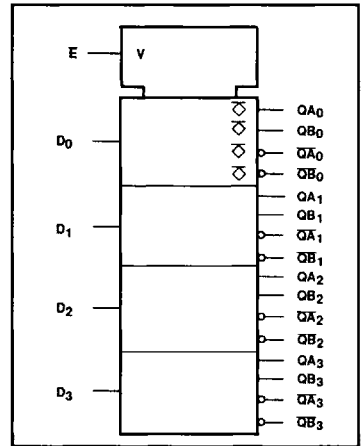
The 100112 has four, 2–input OR–NOR gates. One input from each gate is tied together to form a common enable. Each gate has two OR outputs and two NOR outputs. For a faster version of this part, see the 100113.

All unused inputs can be left open due to integrated pull–down resistors.

PIN DESCRIPTION

PINS	DESCRIPTION
$D_0 - D_3$	Data Inputs
E	Enable Input
$QA_0 - QA_3$, $QB_0 - QB_3$	True Data Outputs (OR)
$\overline{QA}_0 - \overline{QA}_3$, $\overline{QB}_0 - \overline{QB}_3$	Complementary Data Outputs (NOR)

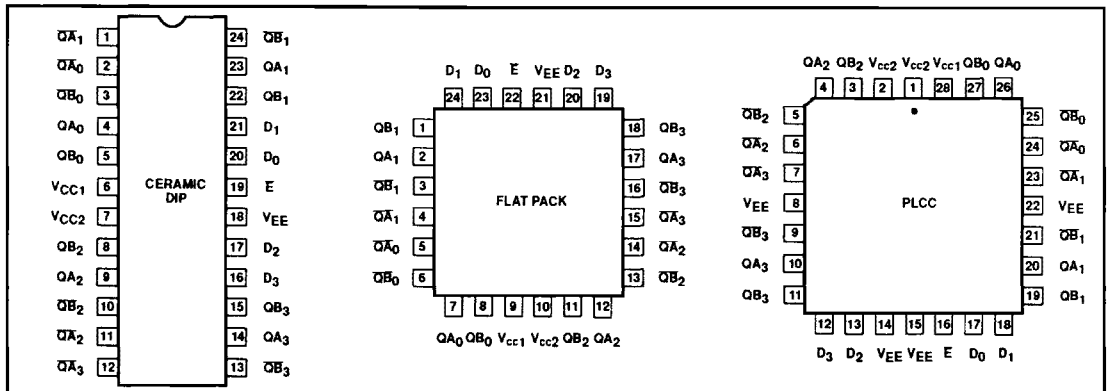
IEC/IEEE SYMBOL



ORDERING INFORMATION

DESCRIPTION	ORDER CODE
24–Pin Ceramic DIP (400 mils wide)	100112F
24–Pin Ceramic Flat Pack	100112Y
28–Pin PLCC	100112A

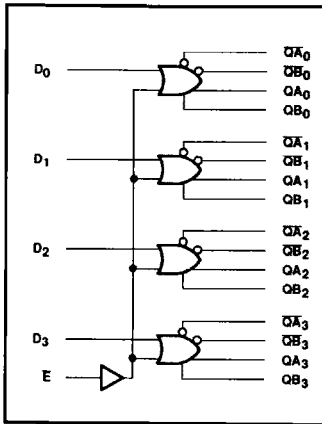
PIN CONFIGURATIONS



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LOGIC DIAGRAM



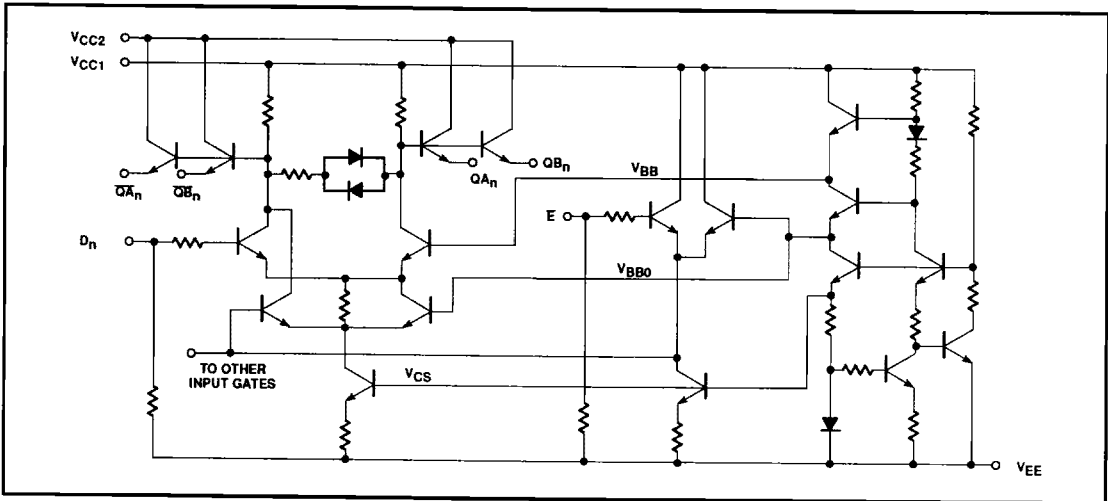
FUNCTION TABLE (One Gate)

INPUTS		OUTPUTS			
D_n	E	QA_n	QB_n	QA_n	QB_n
H	X	L	L	H	H
X	H	L	L	H	H
L	L	H	H	L	L

NOTES:

- H = High voltage level
- L = Low voltage level
- X = Don't care

SIMPLIFIED SCHEMATIC



ABSOLUTE MAXIMUM RATINGS $V_{CC1} = V_{CC2} = \text{ground}$, $T_A = 0^\circ\text{C}$ to $+85^\circ\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	LIMITS	UNIT
V_{EE}	Supply voltage range	-7.0 to +0.5	V
V_{IN}	Input voltage (V_{IN} should never be more negative than V_{EE})	V_{EE} to +0.5	V
I_O	Output source current (continuous)	-55	mA
T_S	Storage temperature range	-65 to +150	$^\circ\text{C}$
T_J	Maximum junction temperature	+150	$^\circ\text{C}$

NOTE:

Operation beyond the limits set forth in this table may impair the useful life of the device.

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DC OPERATING CONDITIONS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS			UNIT
			MIN.	NOM.	MAX.	
V_{CC1}, V_{CC2}	Circuit ground		0	0	0	V
V_{EE}	Supply voltage		-4.8	-4.5	-4.2	V
V_{EE}	Supply voltage when operating with the 10K or 10KH ECL family		-5.7			V
V_{IH}	High level input voltage	$V_{EE} = -4.2V$	-1150		-880	mV
		$V_{EE} = -4.5V$	-1165			
		$V_{EE} = -4.8V$	-1165			
V_{IL}	Low level input voltage	$V_{EE} = -4.2V$	-1810		-1475	mV
		$V_{EE} = -4.5V$			-1475	mV
		$V_{EE} = -4.8V$			-1490	mV
T_A	Operating ambient temperature range		0	+25	+85	°C

NOTE:

When operating at other than the specified V_{EE} voltages (-4.2V, -4.5V, -4.8V), the DC and AC electrical characteristics will vary slightly from their specified values.

DC ELECTRICAL CHARACTERISTICS $V_{CC1} = V_{CC2} = \text{ground}$, $V_{EE} = -4.8V$ to $-4.2V$, $T_A = 0^\circ\text{C}$ to $+85^\circ\text{C}$ unless otherwise specified^{1,3,4}

SYMBOL	PARAMETER	TEST CONDITIONS ²	LIMITS			UNIT		
			MIN.	TYP.	MAX.			
V_{OH}	High level output voltage	Inputs at V_{IHMAX} or V_{ILMIN} .	$V_{EE} = -4.2V$	-1020		-870	mV	
			$V_{EE} = -4.5V$	-1025	-955	-880	mV	
			$V_{EE} = -4.8V$	-1035		-880	mV	
V_{OHT}	High level output threshold voltage	Outputs Loaded	Apply V_{IHMIN} or V_{ILMAX} to one input at a time, other inputs at V_{IHMAX} or V_{ILMIN} .	$V_{EE} = -4.2V$	-1030		mV	
			$V_{EE} = -4.5V$	-1035		mV		
			$V_{EE} = -4.8V$	-1045		mV		
V_{OLT}	Low level output threshold voltage	with 50Ω to -2.0V ±0.010V	Apply V_{IHMIN} or V_{ILMAX} to one input at a time, other inputs at V_{IHMAX} or V_{ILMIN} .	$V_{EE} = -4.2V$		-1595	mV	
			$V_{EE} = -4.5V$		-1610	mV		
			$V_{EE} = -4.8V$		-1610	mV		
V_{OL}	Low level output voltage	Inputs at V_{IHMAX} or V_{ILMIN} .	$V_{EE} = -4.2V$	-1810		-1605	mV	
			$V_{EE} = -4.5V$	-1810	-1705	-1620	mV	
			$V_{EE} = -4.8V$	-1830		-1620	mV	
I_{IH}	High level input current	D_n inputs	One input under test at V_{IHMAX} .			550	μA	
		E input	Other inputs at V_{ILMIN} .			450	μA	
I_{IL}	Low level input current	One input under test at V_{ILMIN} . Other inputs at V_{IHMAX} .			0.5	μA		
$-I_{EE}$	V_{EE} supply current	All inputs at V_{IHMAX} .			51	73	106	mA

NOTES:

- The specified limits represent the worst case values for the parameter. Since these worst case values normally occur at the supply voltage and temperature extremes, additional noise immunity can be achieved by decreasing the allowable operating condition ranges.
- Conditions for testing shown in the tables are not necessarily worst case. For worst case testing guidelines, refer to DC Testing, Chapter 1, Section 3.
- The specified limits shown in the DC electrical characteristics table can be met only after thermal equilibrium has been established. Thermal equilibrium is established by applying power for at least 2 minutes, while maintaining transverse airflow of 2.5 meters/sec (500 linear feet/min) over the device, mounted either in a test socket or on a printed circuit board. Test voltage values are given in the DC operating conditions table.
- The device can function down to $V_{EE} = -5.7V$, allowing operation with either the 10K or the 10KH family. Correction factors can be used to calculate new DC limits for the extended V_{EE} range. For more information, see Chapters 5 and 10, Section 4.

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AC ELECTRICAL CHARACTERISTICS

Ceramic DIP $V_{CC1} = V_{CC2} = \text{ground}$, $V_{EE} = -4.8\text{V to } -4.2\text{V}$

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t_{PLH} t_{PHL}	Propagation delay D_n to $QA_n, QB_n, \overline{QA_n}, \overline{QB_n}$	Waveform 1	0.55	1.40	0.55	1.35	0.45	1.40	ns
			0.55	1.40	0.55	1.35	0.45	1.40	ns
t_{PLH} t_{PHL}	Propagation delay E to $QA_n, QB_n, \overline{QA_n}, \overline{QB_n}$		0.65	1.90	0.65	1.90	0.65	1.90	ns
			0.65	1.90	0.65	1.90	0.65	1.90	ns
t_{TLH} t_{THL}	Transition time all outputs		0.45	1.50	0.45	1.40	0.45	1.50	ns
			0.45	1.50	0.45	1.40	0.45	1.50	ns

NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

AC ELECTRICAL CHARACTERISTICS

Ceramic DIP $V_{CC1} = V_{CC2} = \text{ground}$, $V_{EE} = -5.2\text{V} \pm 5\%$

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t_{PLH} t_{PHL}	Propagation delay D_n to $QA_n, QB_n, \overline{QA_n}, \overline{QB_n}$	Waveform 1	0.55	1.40	0.55	1.35	0.45	1.40	ns
			0.55	1.40	0.55	1.35	0.45	1.40	ns
t_{PLH} t_{PHL}	Propagation delay E to $QA_n, QB_n, \overline{QA_n}, \overline{QB_n}$		0.65	1.90	0.65	1.90	0.65	1.90	ns
			0.65	1.90	0.65	1.90	0.65	1.90	ns
t_{TLH} t_{THL}	Transition time all outputs		0.45	1.50	0.45	1.40	0.45	1.50	ns
			0.45	1.50	0.45	1.40	0.45	1.50	ns

NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

AC ELECTRICAL CHARACTERISTICS

Flat Pack and PLCC $V_{CC1} = V_{CC2} = \text{ground}$, $V_{EE} = -4.8\text{V to } -4.2\text{V}$

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t_{PLH} t_{PHL}	Propagation delay D_n to $QA_n, QB_n, \overline{QA_n}, \overline{QB_n}$	Waveform 1	0.55	1.20	0.55	1.15	0.45	1.20	ns
			0.55	1.20	0.55	1.15	0.45	1.20	ns
t_{PLH} t_{PHL}	Propagation delay E to $QA_n, QB_n, \overline{QA_n}, \overline{QB_n}$		0.65	1.70	0.65	1.70	0.65	1.70	ns
			0.65	1.70	0.65	1.70	0.65	1.70	ns
t_{TLH} t_{THL}	Transition time all outputs		0.45	1.50	0.45	1.40	0.45	1.50	ns
			0.45	1.50	0.45	1.40	0.45	1.50	ns

NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

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AC ELECTRICAL CHARACTERISTICS

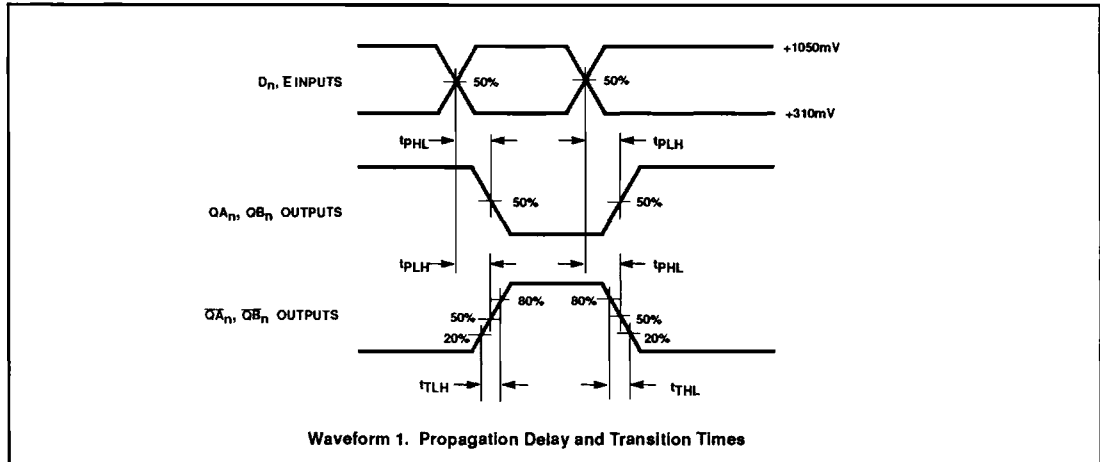
Flat Pack and PLCC $V_{CC1} = V_{CC2} = \text{ground}$, $V_{EE} = -5.2V \pm 5\%$

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t_{PLH} t_{PHL}	Propagation delay D_n to $QA_n, QB_n, \overline{QA}_n, \overline{QB}_n$	Waveform 1	0.55	1.20	0.55	1.15	0.45	1.20	ns
			0.55	1.20	0.55	1.15	0.45	1.20	
t_{PLH} t_{PHL}	Propagation delay E to $QA_n, QB_n, \overline{QA}_n, \overline{QB}_n$		0.65	1.70	0.65	1.70	0.65	1.70	ns
			0.65	1.70	0.65	1.70	0.65	1.70	
t_{TLH} t_{THL}	Transition time all outputs		0.45	1.50	0.45	1.40	0.45	1.50	ns
			0.45	1.50	0.45	1.40	0.45	1.50	

NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

AC WAVEFORMS



NOTE:

All power and signal voltages shifted up 2.0V for AC bench test purposes.